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2829

**\*\*CONTINUING DATA VERIFIED:**  
*none*

**\*\* FOREIGN APPLICATIONS VERIFIED:**  
JAPAN 2001-78362 03/19/2001  
JAPAN 2001-78363 03/19/2001

PG-PUB	DO NOT PUBLISH <input checked="" type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 conditions met <input checked="" type="checkbox"/> yes <input type="checkbox"/> no Verified and Acknowledged Examiners's initials		ATTORNEY DOCKET NO 12844.3US01

**TITLE :** Method and apparatus for automatically testing semiconductor device

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<b>ISSUE FEE</b> Amount Due: Date Paid: <input type="checkbox"/> <b>TERMINAL</b> <b>DISCLAIMER</b>		<b>Assistant Examiner</b>   <b>Primary Examiner</b>  <b>PREPARED FOR ISSUE</b>	<b>Application Examiner</b>   
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